

AVALANCHE FAST SOFT-RECOVERY RECTIFIER DIODES

Rectifier diodes in hermetically sealed axial-leaded ID* envelopes. They are intended for television and industrial applications, such as switched-mode power supplies, scan rectifiers in TV receivers and also for use in inverter and converter applications. The devices feature non-snap-off (soft-recovery) switching characteristics and are capable of absorbing reverse transient energy (e.g. during flashover in a picture tube).

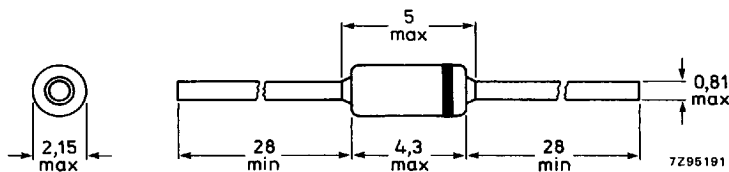
QUICK REFERENCE DATA

			BYD33D	G	J	K	M
Repetitive peak reverse voltage	V_{RRM}	max.	200	400	600	800	1000 V
Continuous reverse voltage	V_R	max.	200	400	600	600	1000 V
Average forward current	$I_F(AV)$	max.	1,3			1,3	A
Non-repetitive peak forward current	I_{FSM}	max.	20			20	A
Non-repetitive peak reverse energy	E_{RSM}	max.	10			7	mJ
Reverse recovery time	t_{rr}	<	250			300	ns

MECHANICAL DATA

Dimensions in mm

Fig. 1 SOD-81.



The marking band indicates the cathode.

* Implosion Diode.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

		BYD33D	G	J	K	M
Repetitive peak reverse voltage	V_{RRM} max.	200	400	600	800	1000 V
Continuous reverse voltage	V_R max.	200	400	600	800	1000 V
Average forward current (averaged over any 20 ms period)						
$T_{tp} = 55\text{ }^\circ\text{C}$; lead length 10 mm	$I_{F(AV)}$ max.		1,3		1,3	A
$T_{amb} = 65\text{ }^\circ\text{C}$; see Fig. 2	$I_{F(AV)}$ max.		0,7		0,7	A
Repetitive peak forward current						
$T_{tp} = 55\text{ }^\circ\text{C}$; see Fig. 10	I_{FRM} max.		12		12	A
$T_{amb} = 65\text{ }^\circ\text{C}$; see Fig. 11	I_{FRM} max.		7		7	A
Non-repetitive peak forward current						
$t = 10$ ms, half-sine wave;						
$T_j = T_j$ max prior to surge;						
$V_R = V_{RRMmax}$	I_{FSM} max.		20		20	A
Non-repetitive peak reverse avalanche energy; $I_R = 400$ mA; $T_j = T_j$ max, prior to surge; with inductive load switched off	ER_{SM} max.		10		7	mJ
Storage temperature	T_{stg}		-65 to +175			$^\circ\text{C}$
Junction temperature	T_j max.		175			$^\circ\text{C}$

THERMAL RESISTANCE

Influence of mounting method

1. Thermal resistance from junction to tie-point at a lead length of 10 mm
2. Thermal resistance from junction to ambient; device mounted on a 1,5 mm thick epoxy-glass printed circuit board; Cu-thickness $\geq 40\text{ }\mu\text{m}$; Fig. 2 (see "Thermal Model")

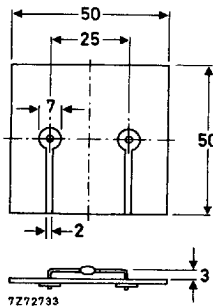


Fig. 2 Mounted on a printed-circuit board.

CHARACTERISTICS

$T_j = 25\text{ }^\circ\text{C}$ unless otherwise specified

		BYD33D	G	J	K	M
Forward voltage*	$I_F = 1\text{ A}$	$V_F < 1,3$	1,3	1,3	1,3	1,3 V
	$I_F = 1\text{ A}; T_j = T_{j\text{ max}}$	$V_F < 1,1$	1,1	1,1	1,1	1,1 V
Reverse avalanche breakdown voltage	$I_R = 0,1\text{ mA}$	$V_{(BR)R} > 300$	500	700	900	1100 V
Reverse current	$V_R = V_{RRM\text{max}}^{**}$	$I_R < 1$	1		1	μA
	$V_R = V_{RRM\text{max}}; T_j = 165\text{ }^\circ\text{C}$	$I_R < 100$	100		100	μA
Reverse recovery when switched from $I_F = 1\text{ A}$ to $V_R \geq 30\text{ V}$ with $-dI_F/dt = 20\text{ A}/\mu\text{s}$	recovery charge	$Q_s < 250$	250		400	nC
	recovery time	$t_{rr} < 250$	250		300	ns
Maximum slope of reverse recovery current when switched from $I_F = 1\text{ A}$ to $V_R \geq 30\text{ V}$ with $-dI_F/dt = 1\text{ A}/\mu\text{s}$	$ dI_R/dt < 6$		6		5	$\text{A}/\mu\text{s}$

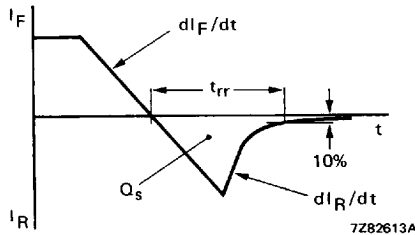


Fig. 3 Definitions of t_{rr} , Q_s , dI_F/dt and dI_R/dt .

* Measured under pulse conditions to avoid excessive dissipation.
** Illuminance $\leq 500\text{ lux}$ (daylight); relative humidity $< 65\%$.

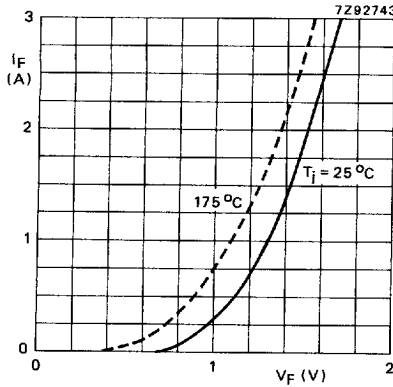


Fig. 4 Maximum forward voltage.

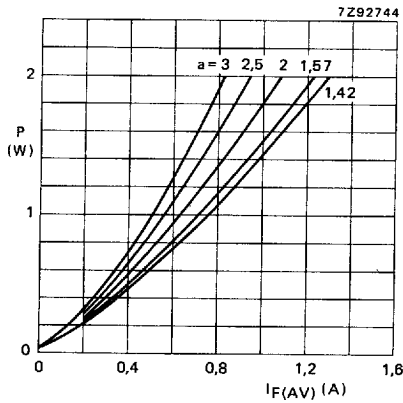


Fig. 5 Maximum values steady state power dissipation (forward plus leakage current) excluding switching losses as a function of the average forward current.

The graph is for switched-mode application.

$a = I_F(RMS)/I_F(AV)$; $V_R = V_{RRM \max}$

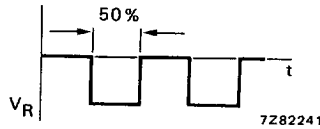
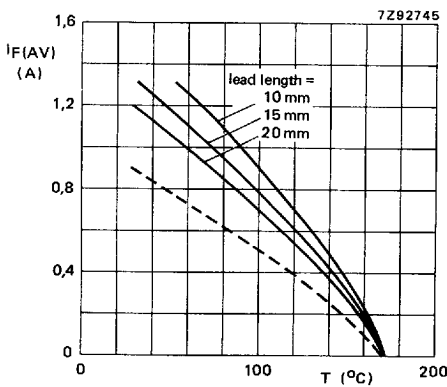


Fig. 6 Maximum average forward current as a function of temperature; the curves include losses due to reverse leakage.

The graph is for switched-mode application.

$V_R = V_{RRM \max}$, $\delta = 0,5$; $a = 1,42$.

- - - = ambient temperature and device mounted as shown in Fig. 2
- = tie-point temperature



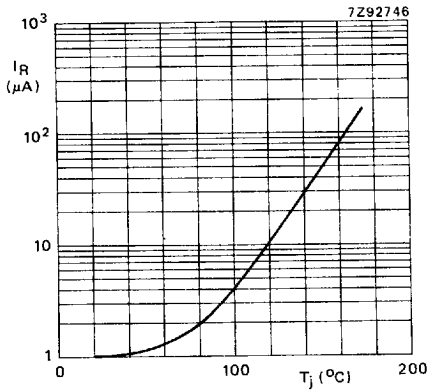


Fig. 7 Maximum values reverse current as a function of junction temperature; $V_R = V_{RRM \max}$.

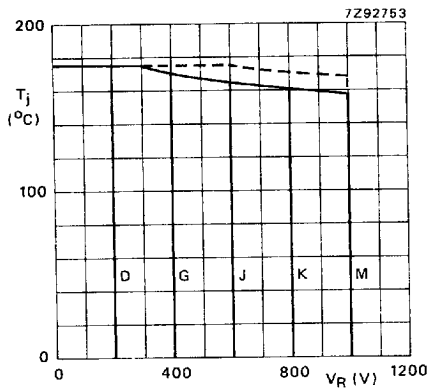


Fig. 8 Maximum permissible junction temperature as a function of reverse voltage;
— = V_R ; --- = V_{RRM} , $\delta = 0,5$.

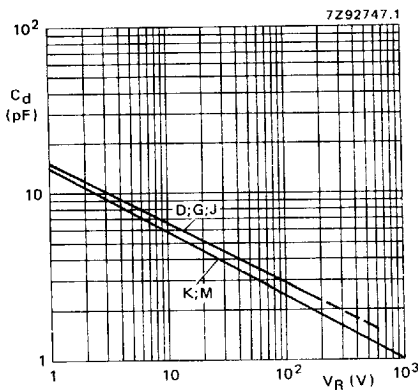


Fig. 9 Capacitance as a function of reverse voltage; $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ\text{C}$; typical values.

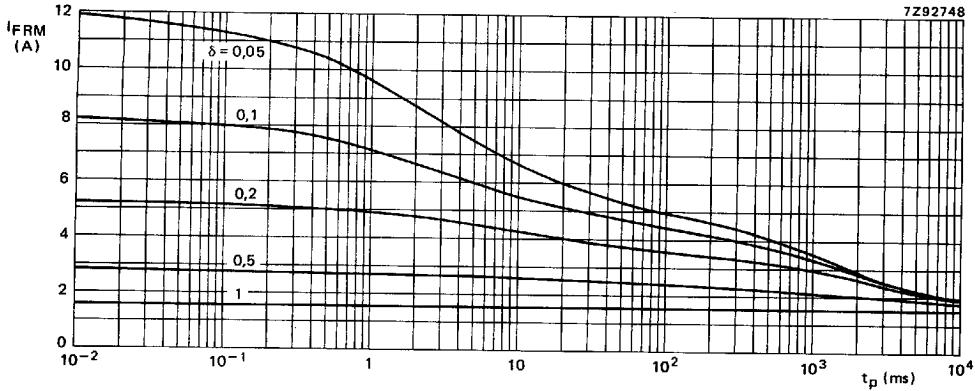


Fig. 10 Maximum repetitive peak forward current as a function of the pulse time (square pulse) and duty-factor δ at $T_{\text{tie-point}} = 55^\circ\text{C}$; $R_{\text{th j-tp}} = 60 \text{ K/W}$; V_{RRM} during $1 - \delta$; the curves include derating for $T_{\text{j max}}$ at $V_{\text{RRM}} = 1000 \text{ V}$.

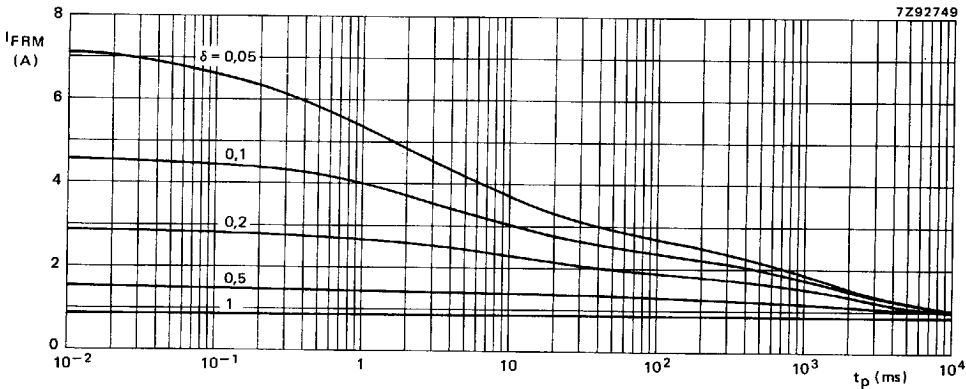


Fig. 11 Maximum repetitive peak forward current as a function of the pulse time (square pulse) and duty-factor δ at $T_{\text{amb}} = 65^\circ\text{C}$; $R_{\text{th j-a}} = 120 \text{ K/W}$; V_{RRM} during $1 - \delta$; the curves include derating for $T_{\text{j max}}$ at $V_{\text{RRM}} = 1000 \text{ V}$.